

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Timothy B. Cowles and Christian
N. Mohr

Serial No.:

Filed: May 24, 2001

For: CIRCUIT AND METHOD FOR TEST AND
REPAIR

§ Group Art Unit:
§ Examiner:
§ Atty. Docket: 2000-0058.01
§

JC971 U.S. PTO
09/064682
05/24/01

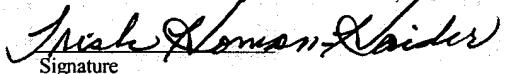
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
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Dear Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, Applicants respectfully request that this Information Disclosure Statement be entered and that the references listed on the attached Form PTO-1449 be considered by the Examiner and made of record.. Copies of the listed references are enclosed for the convenience of the Examiner.

In accordance with 37 C.F.R. § 1.97(b), this Information Disclosure Statement is not to be construed as a representation that a search has been made or that no other possible material information as defined in 37 C.F.R. § 1.56(a) exists.

The following references are submitted for the Examiner's review:

U.S. Patents

<u>U.S. Patent No.</u>	<u>Issue Date</u>	<u>Inventor</u>
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6,154,851	11/28/00	Sher et al.
6,154,398	11/28/00	Cutter et al.
6,145,092	11/07/00	Beffa et al.
6,144,593	11/07/00	Cowles et al.
6,130,834	10/10/00	Mullarkey et al.
6,119,251	09/12/00	Cloud et al.
6,104,645	08/15/00	Ong et al.
6,088,282	07/11/00	Loughmiller et al.
5,959,929	09/28/99	Cowles et al.
5,917,764	06/29/99	Ohsawa et al.
5,910,921	06/08/99	Beffa et al.
5,883,843	03/16/99	Hii et al.
5,724,282	03/03/98	Loughmiller et al.
5,655,105	08/05/97	McLaury

Other References

Cowles, Timothy B., "Circuit and Method for Test and Repair," application serial No. 09/810,366, filed March 15, 2001.

Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x4, x8, x16 SDRAM, 128MSDRAM_ Rev B_, p65; Pub. 10/00, pp. 1-58.

Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x32 SDRAM, 128Mb: x32 DRAM, 128MbSDRAMx32, p65 – Rev. 9/00, pp. 1-52.

As this information is being submitted within three months of the date of filing of the application, Applicants understand that no fee or certification is required for the submission and consideration of this information at this time.

* * * *

A Form PTO-1449 is enclosed herewith.

Respectfully submitted,

512411

Date: Charles Brantley

Charles Brantley
Reg. No. 38,086
Micron Technology, Inc.
8000 S. Federal Way
Boise, ID 83716-9632
(208) 368-4557
ATTORNEY FOR APPLICANTS

FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 2000-0058.01	Serial No: 5091864682
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Applicant: Timothy B. Cowles et al.	Group: 5/24/01
<i>(use several sheets if necessary)</i>		PRO 5/24/01	

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	
DT	AA 6,154,851	11/28/00	Sher et al.	714	005	
	AB 6,154,398	11/28/00	Cutter et al.	365	200	
	AC 6,145,092	11/07/00	Beffa et al.	714	007	
	AD 6,144,593	11/07/00	Cowles et al.	365	200	
	AE 6,130,834	10/10/00	Mullarkey et al.	365	096	
	AF 6,119,251	09/12/00	Cloud et al.	714	718	
	AG 6,104,645	08/15/00	Ong et al.	365	200	
	AH 6,088,282	07/11/00	Loughmiller et al.	365	225.7	
	AI 5,959,929	09/28/99	Cowles et al.	365	230.03	
	AJ 5,917,764	06/29/99	Ohsawa et al.	365	200	
	AK 5,910,921	06/08/99	Beffa et al.	365	201	
	AL 5,883,843	03/16/99	Hii et al.	365	201	
DT	AM 5,724,282	03/03/98	Loughmiller et al.	365	096	
	AN 5,655,105	08/05/97	McLaury	395	496	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes	Translation No
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>
	AQ					<input type="checkbox"/>	<input type="checkbox"/>

Initial **OTHER ART** (including author, title, date, pertinent pages, etc.)

DT	AR	1	Cowles, Timothy B., "Circuit and Method for Test and Repair," application serial No. 09/810,366, filed March 15, 2001.
DT	AS	2	Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x4, x8, x16 SDRAM, 128MSDRAM_ Rev B_, p65; Pub. 10/00, pp. 1-58.
DT		3	Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x32 SDRAM, 128Mb: x32 DRAM, 128MbSDRAMx32, p65 – Rev. 9/00, pp. 1-52.

Examiner:	<i>Dandron</i>	Date Considered:	<i>7/9/04</i>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.